

#### **Features**

- High isolation 5000 VRMS
- Patented coplanar structure DMC-Isolator®
- DC input with transistor output
- Operating Temperature range 55 °C to 110 °C
- External Creepage ≥ 7.4mm
- Distance Through Isolation ≥ 0.4mm
- Clearance Distance ≥ 7.5mm (S/SL Type)
- Clearance Distance ≥ 8.0mm (M Type)
- RoHS and REACH Compliance
- Halogen Free Compliance (Optional)
- MSL class 1
- Regulatory Approvals
  - ✓ UL UL1577 (E364000)
  - ✓ VDE EN60747-5-5(VDE0884-5)
  - ✓ CQC GB4943.1, GB8898 (14001105802)
  - ✓ IEC62368 (FI/41119)

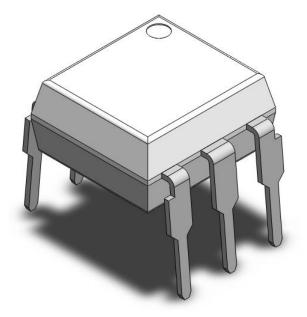
### **Description**

The 4N25, 4N26, 4N27, 4N28, 4N35, 4N36, 4N37, 4N38, H11A1, H11A2, H11A3, H11A4, H11A5 series consist of a photo transistor optically coupled to an Infrared-emitting diode in a 6-lead DIP DMC-Isolator® package with different lead forming options.

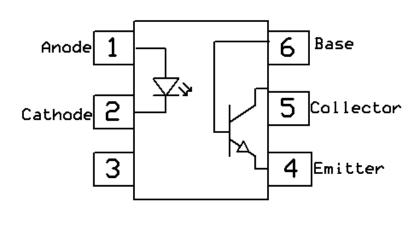
# **Applications**

- Microprocessor system interface
- Computer peripheral interface
- Switch mode power supplies

# **Package Outline**



## **Schematic**



Note: Different bending options available. See package dimension.



# Absolute Maximum Ratings $T_A = 25$ °C, unless otherwise specified

Stresses in excess of the absolute maximum ratings can cause permanent damage to the device. Functional operation of the device is not implied at these or any other conditions in excess of those given in the operational sections of this document. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameters	Ratings	Units	Notes
Viso	Isolation voltage (AC, 1 minute, 40 ~ 60% R.H.)	5000	V <sub>RMS</sub>	
Topr	Operating temperature	-55 ~ +110	°C	
Tstg	Storage temperature	-55 ~ +150	°C	
TsoL	Soldering temperature (For 10 seconds)	260	°C	
Emitter		·		
l <sub>F</sub>	Forward current	60	mA	
I <sub>F(TRANS)</sub>	Peak transient current (≤1µs P.W,300pps)	1	А	
V <sub>R</sub>	Reverse voltage	6	V	
P <sub>D</sub>	Power dissipation	100	mW	
Detector		·		
P <sub>D</sub>	Power dissipation	150	mW	
Bvceo	Collector-Emitter Breakdown Voltage	80	V	
Вусво	Collector-Base Breakdown Voltage	80	V	
Bveco	Emitter-Collector Breakdown Voltage	7	V	
Вуево	Emitter-Base Breakdown Voltage	7	V	



# **Electrical Characteristics** $T_A = 25^{\circ}$ C, unless otherwise specified

#### **Emitter Characteristics**

Symbol	Parameters	Test Conditions	Min	Тур	Max	Units	Notes
VF	Forward voltage	I <sub>F</sub> =10mA		1.24	1.4	V	
I <sub>R</sub>	Reverse Current	V <sub>R</sub> = 6V	-	-	5	μA	
Cin	Input Capacitance	f= 1MHz	-	45	-	pF	

#### **Detector Characteristics**

Symbol	Pa	rameters	Test Conditions	Min	Тур	Max	Units	Notes
B <sub>VCEO</sub>	Collector-Emitter I	Breakdown	I <sub>C</sub> = 0.1mA	80	-	-	V	
Bveco	Emitter-Collector I	Breakdown	I <sub>E</sub> = 0.1mA	7	-	-	V	
Вусво	Collector-Base Breakdown		Ic= 0.1mA	80	-	-	V	
B <sub>VEBO</sub>	Emitter-Base Breakdown		I <sub>E</sub> = 0.1mA	7	-	-	V	
I <sub>CEO</sub>	Collector-Emitter  Dark Current	4N25,4N26,4N27,4N28 H11A1,A2,A3,A4,A5	V <sub>CE</sub> = 10V, I <sub>F</sub> =0mA	-	-	50	nA	
		4N35,4N36,4N37,4N38	V <sub>CE</sub> =60V, I <sub>F</sub> =0mA	-	-	50	nA	
Ісво	Collector-Base Dark Current		V <sub>CB</sub> = 10V, I <sub>F</sub> =0mA	-	-	20	nA	



# **Electrical Characteristics** $T_A = 25$ °C, unless otherwise specified (Continued)

#### **Transfer Characteristics**

Symbol	F	Parameters	Test Conditions	Min	Тур	Max	Units	Notes
		4N35, 4N36, 4N37	I <sub>F</sub> = 10mA, V <sub>CE</sub> = 10V	100	-	-	- %	
	Command	4N25,4N26, 4N38,		20	-	-		
OTD	Current	H11A2, H11A3						
CTR	Transfer	4N27, 4N28, H11A4		10	-	-		
	Ratio	H11A1		50	-	-		
		H11A5		30	-	-		
		4N25,4N26,	I <sub>F</sub> = 50mA, I <sub>C</sub> = 2mA			0.5		
	Collector-E	4N27,4N28		-	-	0.5		
V	mitter	4N35,4N36,4N37		-	-	0.3	V	
V <sub>CE(SAT)</sub>	Saturation	H11A1,H11A2,	I <sub>F</sub> = 10mA, I <sub>C</sub> = 0.5mA			0.4	V	
	Voltage	H11A3,H11A4,H11A5		-	-	0.4		
		4N38	I <sub>F</sub> = 20mA, I <sub>C</sub> = 4mA	-	-	1.0		
Rio	Isolation Resistance		V <sub>IO</sub> = 500V <sub>DC</sub>	1x10 <sup>11</sup>	-		Ω	
C <sub>IO</sub>	Isolation Capacitance		f= 1MHz		0.25		pF	

## **Switching Characteristics**

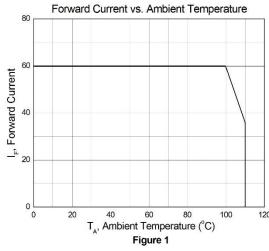
Symbol	Parameters		Test Conditions	Min	Тур	Max	Units	Notes
	Turn On ton	4N25,4N26,4N27,4N28	I <sub>F</sub> = 10mA, V <sub>CC</sub> = 10V, R <sub>L</sub> =	1	4.0	0.0		
		H11A1,A2,A3,A4,A5	100Ω		4.3	9.8		
lon		4NOC 4NOC 4NOT 4NOC	I <sub>c</sub> = 2mA, V <sub>CC</sub> = 10V, R <sub>L</sub> =		0.0	11.5	- µs	
		4N35,4N36,4N37,4N38	100Ω	-	9.8			
		4N25,4N26,4N27,4N28	I <sub>F</sub> = 10mA, V <sub>CC</sub> = 10V, R <sub>L</sub> =		2.0	0.0		
4	Turn Off H11A1,A2,A3,A4,A5 $100\Omega$ Time $I_c$ = 2mA, $100\Omega$	100Ω	- 3.9	9.8				
t <sub>off</sub>		4NDE 4NDE 4NDT 4ND	I <sub>c</sub> = 2mA, V <sub>CC</sub> = 10V, R <sub>L</sub> =		0.0 44.5	44 E	μs	
		100Ω	- 6.	6.9	11.5			

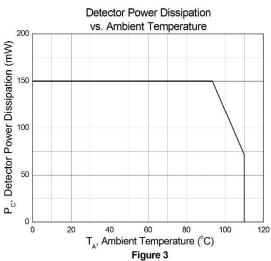
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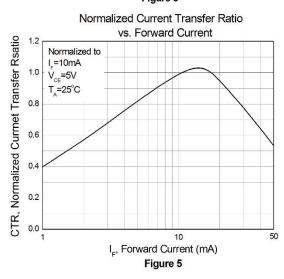
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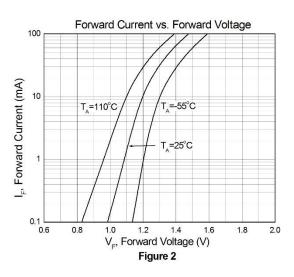


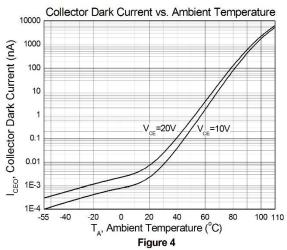
## Typical Characteristic Curves $T_A = 25$ °C, unless otherwise specified

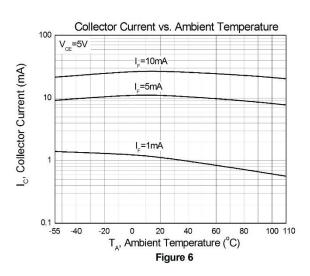






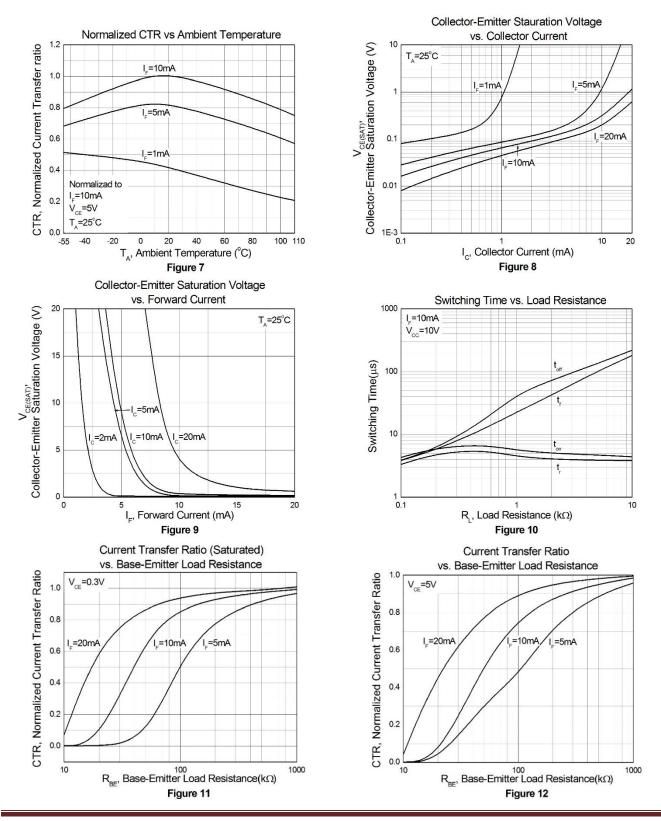






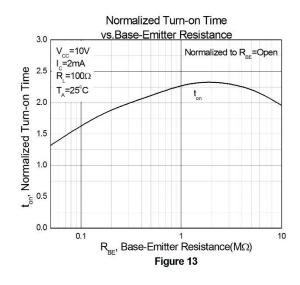


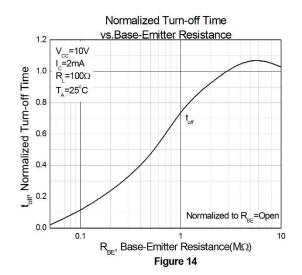
## Typical Characteristic Curves $T_A = 25$ °C, unless otherwise specified (Continued)





# Typical Characteristic Curves $T_A = 25$ °C, unless otherwise specified (Continued)

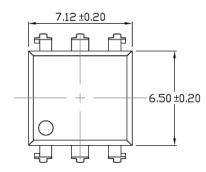


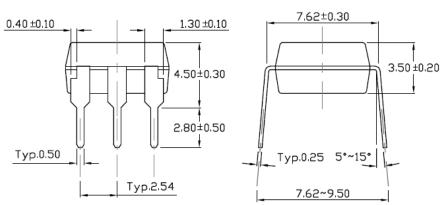




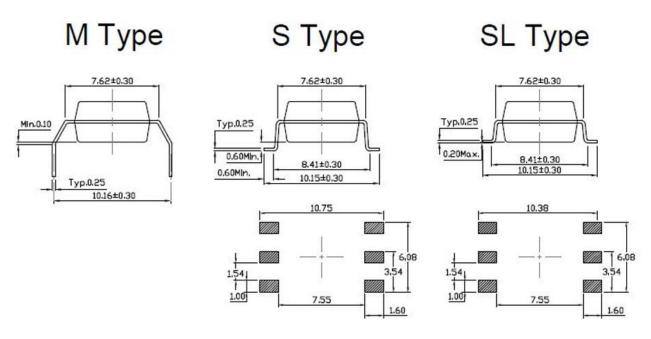
### Package Dimension Dimensions in mm unless otherwise stated

### Standard DIP - Through Hole



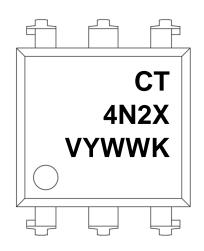


# **Forming Option**





## **Marking Information**



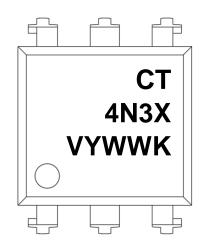
#### Note:

CT : Denotes "CT Micro"

4N2X : Part Number (X=5,6,7 or 8)

V : VDE Safety Mark Option (Blank or V)

Y : One Digit Year CodeWW : Two Digit Work WeekK : Manufacturing Code



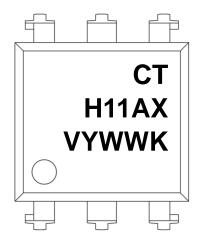
#### Note:

CT : Denotes "CT Micro"

4N3X: Part Number (X=5,6,7 or 8)

V : VDE Safety Mark Option (Blank or V)

Y : One Digit Year CodeWW : Two Digit Work WeekK : Manufacturing Code



#### Note:

CT : Denotes "CT Micro"

H11AX: Part Number (X=1,2,3,4 or 5)

V : VDE Safety Mark Option (Blank or V)

Y : One Digit Year CodeWW : Two Digit Work WeekK : Manufacturing Code

## **Ordering Information**

# 4N2X(V)(Y)(Z)-G, 4N3X(V)(Y)(Z)-G

X = Part Number (X=5,6,7 or 8)

V = VDE Safety Mark Option (Blank or V)

Y = Lead Form Option (Blank, M, S or SL)

Z = Tape and Reel Option (Blank, T1 or T2)

G = Material Option (G: Halogen Free, Blank: Non-Halogen Free)

# H11AX(V)(Y)(Z)-G

X = Part Number (1,2,3,4 or 5)

V = VDE Safety Mark Option (Blank or V)

Y = Lead Form Option (Blank, M, S or SL)

Z = Tape and Reel Option (Blank, T1 or T2)

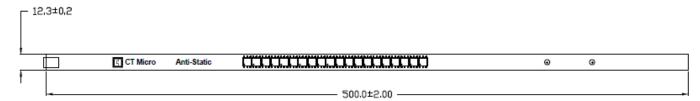
G = Material Option (G: Halogen Free, Blank: Non-Halogen Free)

Option	Description	Quantity
None	None Standard 6 Pin Dip	
M	Wide Lead Forming	50Units/Tube
S(T1)	Surface Mount Lead Forming – With Option A Taping	1000 Units/Reel
S(T2)	Surface Mount Lead Forming – With Option B Taping	1000 Units/Reel
SL(T1)	Surface Mount Lead Forming (Low Profile) – With Option A Taping	1000 Units/Reel
SL(T2)	Surface Mount Lead Forming (Low Profile) – With Option B Taping	1000 Units/Reel

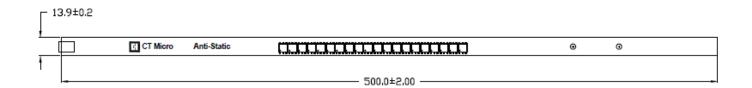


# Carrier Specifications Dimensions in mm unless otherwise stated

### **Tube Option Standard DIP**

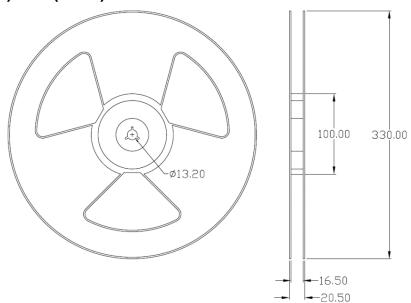


# **Tube Option M Type**



# Reel Dimension All dimensions are in mm, unless otherwise stated

## **Option S(T1/T2) & SL(T1/T2)**

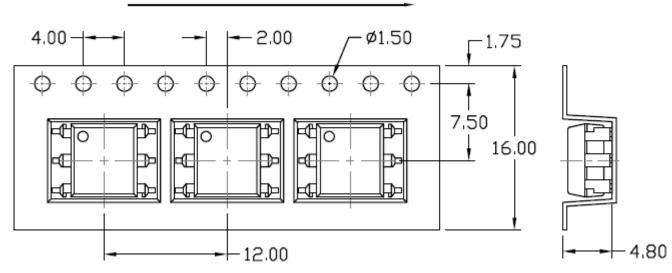




### Carrier Tape Specifications Dimensions in mm unless otherwise stated

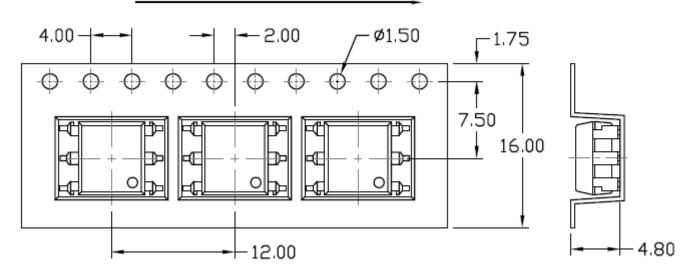
Option S (T1) & SL (T1)

# Input Direction



#### Option S (T2) & SL (T2)

# Input Direction



## Solderability spec (follow the JEDEC standard JESD22-B102)

Reflow Soldering: Immersed surface, other than the end of pin as cut-surface, must be covered by solder.

Solder-Bath: More than 95% of the electrode must be covered with solder.

## **Wave soldering (follow the JEDEC standard JESD22-A111)**

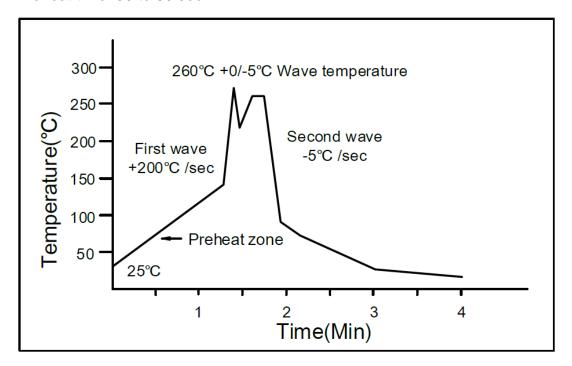
One time soldering is recommended within the condition of temperature.

Temperature: 260+0/-5°C.

Time: 10 sec.

Preheat temperature: 25 to 140°C.

Preheat time: 30 to 80 sec.



# Iron Soldering (follow the standard MIL-STD 202G, Method 210F)

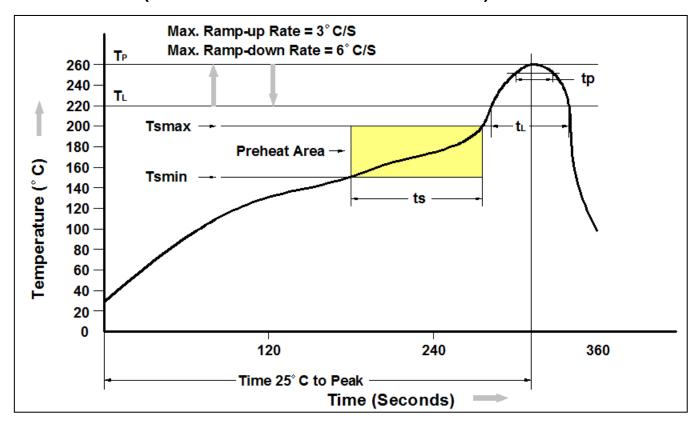
Allow single lead soldering in every single process.

One time soldering is recommended.

Temperature: 350±10°C

Time: 5 sec max.

# Reflow Profile (follow the JEDEC standard J-STD-020)



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (Tsmin)	150°C
Temperature Max. (Tsmax)	200°C
Time (ts) from (Tsmin to Tsmax)	60-120 seconds
Ramp-up Rate (t∟ to t♭)	3°C/second max.
Liquidous Temperature (T <sub>L</sub> )	217°C
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t <sub>P</sub> ) within 5°C of 260°C	30 seconds
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



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